

SMART SENSING INSTRUMENTS  
HIGH ACCURACY RUGGED INSTRUMENTS

(978) 494-0802

## PORTABLE RAMAN SPECTROMETER



### FEATURES

Point, Shoot, Identify with 785nm Excitation with Much Lower Fluorescence than 532nm

High Precision Laser Module

High Precision Spectrometer Module

Cooled Detector with Low Noise Detection

Flexible Probe Design

Very Short or Long Scan Time

Narrow Linewidth or Regular Butterfly Laser

Battery or DC Wall Adapter Powered, On Board Charging

Field Portable, All-in-One Box, Compact and Durable

External USB Devices Supported

CSV or SPC Compatible with Third Party Software

Minimum Maintenance Required

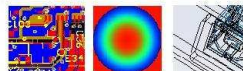
SSI Expertise Technical Support

Economic price

### SPECIFICATIONS

Operating Temperature -10C to 40C

Humidity 10%-85% non condensation



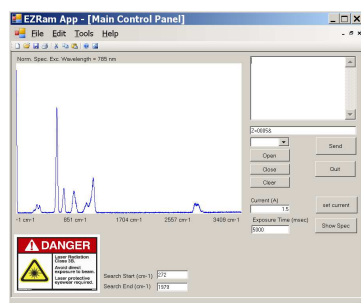
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Spectral Range	250-2880 cm <sup>-1</sup>
Excitation Wavelength	785nm+/-0.5nm FWHM 0.2nm or regular
Excitation Power	Adjustable, 0-350 mW Max
Spectral Resolution	10 cm <sup>-1</sup>
Exposure time	20 usec – 80 sec
System Measurement Accuracy	2% max
Collection Optics	NA = 0.22, 8mm focal length, 0.02-1.5mm spot size
Probe Length	75 – 100cm
Detector Cooling	TEC Cooled to -30 C
Dynamic Range	1300:1 at least
Power Supply (Battery Charger Supply)	+12VDC , 5A
Battery	LiPoly, Optional
Battery Charger	On board, Optional
Library	Optional
Data Export Format	*.CSV, *.SPC
Interface	Windows Tablet or PC
Language	English
Weight	10lb
Size	14in x 12.5in x 7in
* probe shape, probe color, enclosure's handle color might vary	

## EZRAM SOFTWARE

Background removable	Included
Digital Filtering	Included
Single element library search	Included
Mixer library build	Included
Mixer library search	N/A
Operating System Requirement	Windows



Sample spectrum using a regular laser, FWHM = 2nm

To Send Quotation:

Email: [smartsensinginternational@gmail.com](mailto:smartsensinginternational@gmail.com)

Telephone: 978-494-0802

**Warning: CLASS IIb LASER PRODUCT AVOID DIRECT EXPOSURE TO BEAM**